			APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL								Page 1	1
E E	SCC	C	omponent Title:	INT MC	TEGRATED C DULATOR	IRCUITS, S	SILICO	N MON	OLITHIC, PULSE WIDT	Appl. N	0.	
C 400		E	Executive Member: CNES Date: 07/07/2021						344B			
Components (includi	ng series and famili	ies) sı	ubmitted for Exte	ension	of Qualification	n Approva	:					1
ESCC COMPONENT NO.	ESCC MPONENT VARIANTS			RANGE OF COMPONENTS			BASED ON		TEST VEHICLE / S	COMPONENT SIMILAR		Т
9108 020	01; 02					Туре	ST1843	3	9108 020 01F	9108 020 01F All variant		
9108 021	01; 02					Туре	ST184	5	9108 021 01R All v		/ariant	
9201 043	02					Туре	4011B		9201 043 02FR	ST1	843/1845	
										(Se	e box 16)	
Component Ma	anufacturer	2	Location	of Mar	nufacturing Pla	unt(s)	3					4
ST Microelectronics			Rennes 35041	I – Frar	nce	(-)	Ţ	Date	of original gualification a	pprova	d:	
								Date:	14/11/2016			
								Certifi	icate Ref No. 344			
		5					6		7			
ESCC Specifications	used for		Deviations to LVT testing and Detail Specification				Qualification Extension Report					
Maintenance of quali	fication testing:		used:				reference and date:					
Generic: 9000	Issue: 10		No ⊠ Yes □ (supply details in Box 15)				Data	PackPWM_VOQ2020.pd	t 12	2/05/2021		
Detail(s): 9108/02	0 Issue: 4		Deviation from current Specifications:									
9108/02	1 4											
			No 🛛 Yes 🗌 (Supply details)									
0					11 - 114		41-1			5 A)		8
Summary of procurer			LAT Date code			opiicatioi	n (those to ESCC listed i	rirst) / Delivi	ared			
Ventes Nov 2018 oc	t resurig Le					Date cot			Quantity	Delive	Sieu	
2020.xlsx												
				,								γ
PID changes since st	tart of qualification			9	Current PID	Verified b	y:		JB Sauveplane, CNES			10
None 🗌								Na	ame of Excutive Represe	entative	9	
Minor*					Ref No:	8303834	_6 (PV	VM) & 8	097046_30 (generic)			
Major* 🛛 🖂	*Provide details in	box:			Issue:	6 & 30	Date: 11/06/2021					
					Rev Date:	27/11/20	18 & 3	1/05/202	21			· · · · ·
											11	
Current Manufacturing facilities surveyed by:			y: L. Baczkowski CNES			on	06	0/05/20	121			
(Name of Executive Representative) (Date)												
Satisfactory: Yes 🖂 No 🗆 Explain												
Report Reference:	_20210506_CI	RR-S	ТМ	_								

APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL							
ESCC	Component title:	INTEGRATED MODULATOR	CIRCUITS, SILICON M	ONOLITHIC, PULSE WIDTH	Appl. No.		
	Executive Member:	CNES		Date: 07/07/2021	344B		
Failure Analysis, DPA, NCCS av	ailable: Yes	🖾 No	□ (Supply data)		12		
Ref. No's and purposes: 2CSTM003	3 : Missing data for mai	intenance of Qu	alification on time. 2CSTI	M003rev1 as NCCS close-out (ap	pended).		
The undersigned hereby certifies on behal that the appropriate documentation has be (except as stated in box 15;) - that the rep- CNES as the responsible Executive Mem	f of the ESCC Executiv en evaluated; - that ful orts and data are availa ber for ESCC qualifica	re - that the abo I compliance to able at the ESC(tion status to be	ve information is correct; all ESCC requirements is C Executive and therefore extended to the compor	s evidence e applies on behalf of nent(s) listed herein.	13		
Date: 08/07/2021				JP. BUSSENO (Signature of the Executive	T Coordinator)		
Continuation of Boxes above:					14		

APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL								
C. See	ESCC	Component	t title: INTEGRATED CIRCUIT MODULATOR	S, SILICON MC	DNOLITHIC, PULSE WIDTH	Appl. N	1 0.	
	a to	Executive Member: CNES		I	Date: 07/07/2021	344E	3	
Non comp	bliance to ESCC requirements:						15	
No.:	Specification		Paragraph		Non compliance			
Additional	l I tasks required to achieve full co liance:	mpliance for I	ESCC qualification or rationale for a	acceptability of			16	
To accum series in f following r - - - -	ulate data on a recent date code lat pack 14 package. Indeed, bot reasons: Same die attach is used Same backside Same metal layer Same wire bonding diameter	lot, Chart F4 h HCC40xxx	SG1 & SG3 tests (environmental/ and ST1843 products in flat pack 8	nechanical/asse	embly capability) are performed o erered as similar for the tests perf	n HCC40xxx	e	
Executive	Manager Disposition						17	
Applicatio Action / R	n Approval: Yes ⊠ lemarks:	No 🗆			Britta Schade	Illy signed tta Schac 2021.08.3	d de 31 0'	
Date:					B. Schade: Head of the Produc and Safety Department	t Assurance	-	

APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL										
ESCC	Component Title:	INTEGRATED CIRCUITS, SILICON MODULATOR	MONOLITHIC, PULSE WIDTH	Appl. No.						
	Executive Member	: CNES	Date: 07/07/2021	344B						
ANNEX 1: LIST OF TESTS DONE TO SUF	ANNEX 1: LIST OF TESTS DONE TO SUPPORT EXTENSION OF QUALIFICATION									
Tests conducted in compliance with:										
 ESCC 9000 generic specification; Chart F4 (for ESCC/QPL parts); Or PID-TFD (for ESCC/QML parts) 										
	Based on Type 18	4x :	Based on Type H	ICC40xx :						
ESCC 9108 020 01 ST1843FKG (lot id. 33311002Z1(*) and DC 1917A	33311002Z3) E D	SCC 9108 021 01 T1845RKG (lot id. 33311003YF) (**) C 2033A	ESCC 9201 043 02 HCC4011BKT (lot id. 331 DC 1903A	4000EYD)						
ESCC 9108 020 01 ST1843FKG (lot id. 33311002Z6) DC 1907A	E S D	SCC 9108 021 01 T1845RKG (lot id.33311003YU) C 1942A								
"Engineering lot" ST1843K1 (lot id. 33311002Z5) DC 31904A										
(*) 33311002Z1 is a split from 33311002Z3 done at the end of the screening. Thus they are from same Date Code. (**) 33311003YF is a split from 33311003YG										

Detail Specification reference: 9108/020 ; 9108/021

Chart F4	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if not performed. Comments on Rejection
	Mechanical Shock	\boxtimes	MIL-STD-883, Test Method 2002	1903A	15	0	
	Vibration	\boxtimes	MIL-STD-883, Test Method 2007	1903A	15	0	
	Constant Acceleration	\boxtimes	MIL-STD-883, Test Method 2001	1903A	15	0	
	Seal (Fine and Gross Leak)	\boxtimes	MIL-STD-883, Test Method 1014	1903A	15	0	
chanical Subgroup	Intermediate and End-Point Electrical Measurements	\boxtimes	Intermediate and End-Point Electrical Measurements in the Detail Specification	1903A	15	0	
	External Visual Inspection	\boxtimes	ESCC Basic Specification No. 20500	1903A	15	0	
tal/Me	Thermal Shock	\boxtimes	MIL-STD-883. Test Method 1011	1903A	15	0	
nment	Temperature cycling	\boxtimes	MIL-STD-883, Test Method 1010	1903A	15	0	No test record available
Enviro	Moisture Resistance	\boxtimes	MIL-STD-883, Test Method 1004	1903A	15	0	
	Seal (Fine and Gross Leak)	\boxtimes	MIL-STD-883, Test Method 1014	1903A	15	0	
	Intermediate and End-Point Electrical Measurements	\boxtimes	Intermediate and End-Point Electrical Measurements in the Detail Specification	1903A	15	0	
	External Visual Inspection	\boxtimes	ESCC Basic Specification No. 20500	1903A	15	0	

		31	APPLICATION FOR	Page 5					
C. Sector	ESCC		Component title: INTEGR MODUL	ATED CIRCUI	TS, SILICON	I MONOLITH	Appl. No.		
(and		- E	Executive Member: CNES			Date: 07/07/2021			
1							1		
Chart F4	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if no Comments on	t performed. Rejection	
	Operating Life	\boxtimes	MIL-STD-883, Test Method 1005	1917A 31904A 1907A 2033A 1942A 1903A	13 + 15 + 2 + 15 + 6 + 15	0			
Endurance Subgroup	Intermediate and End-Point Electrical Measurements	\boxtimes	Intermediate and End-Point Electrical Measurements in the Detail Specification	1917A 31904A 1907A 2033A 1942A 1903A	13 + 15 + 2 + 15 + 6 + 15	0			
	Seal (Fine and Gross Leak)	\boxtimes	MIL-STD-883, Test Method 1014	1917A 31904A 1907A 2033A 1942A 1903A	13 + 15 + 2 + 15 + 6 + 15	0			
	External Visual Inspection	\boxtimes	ESCC Basic Specification No. 20500	1917A 31904A 1907A 2033A 1942A 1903A	13 + 15 + 2 + 15 + 6 + 15	0			
roup	Permanence of Marking		ESCC Basic Specification No. 24800				Not applicable for la	ser marking	
/ Subg	Terminal Strength	\boxtimes	MIL-STD-883, Test Method 2004	1903A	5				
Capability	Internal Visual Inspection	\boxtimes	ESCC Basic Specification No. 20400	1903A	5				
mbly (Bond Strength	\boxtimes	MIL-STD-883 Test Method 2011	1903A	2				
Asse	Die Shear or Substrate Attach Strength	\boxtimes	MIL-STD-883 Test Method 2019 or 2027	1903A	2				
onal Tests	RGA		MIL-STD-883 Test Method 1018.7				Only applicable to si qualification of Wire- Integrated Circuits	ngle phase bonded	
Additio									
		<u> </u>		<u> </u>	<u> </u>	<u> </u>	1		

		APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL										
ES	SCC	Component title:	INTEGRATED CIF MODULATOR	CUITS, SILICON MONO	LITHIC, PULSE WIDTH	Appl. No.						
		Executive Member:	CNES	Date	: 07/07/2021	344B						
NOTES ON THE COMPLETION OF THE APPLICATION FORM FOR ESCC QUALIFICATION EXTENSION APPROVA												
ENTRIES Form heading	shall indicate: - the title of the component as given in its detail specification or the name of the series, family; - the Executive Member; - the entering date; - the certificate number and its sequential suffix.											
Box 1	shall provide detai (the ESCC code is the detail specific identifying the con	shall provide details given in the table; in particular there shall be listed: - the variants or range of variants; - the range of components (the ESCC code is recommended to indicate the values or values range, the tolerance, the voltage, etc); the designation given in the detail specification as 'base on'; - under Test Vehicle enter either an ESCC code or the specific characteristic capable of identifying the component tested (e.g., voltage of coil for a relay); - under component similar enter a cross if relevant.										
Box 2; 3 and 4	As per QPL entry;	As per QPL entry; otherwise, an explanation of the changes must be supplied.										
Box 5	Will show the ES reported were per	CC Generic and Deta formed. If the specifica	ail specifications, ind ations are different f	cluding issue number and rom those current on the o	revision letter, current at th late of the application, see B	ne time the tests ox 6.						
Box 6	Will show the devi deviations this mu indicate also whet	ations from the Gene st be listed in Box 15. her the test data devia	ric and Detail Speci In case the referenc ates or not from sucl	ications listed in Box 5, in ed specification in Box 5 l n current documents.	particular deviations from to ave currently a different issu	esting. In case of le and/or revision						
Box 7	Must reference the	e report(s) supplied in	support of the appli	cation.								
Box 8	Should provide the to the ESCC Exec	e details of procurement utive under the terms	nt to the full ESCC S of the relevant Gen	vstem, documentation of a eric Specification. An app	ll of which should already hav opriate table has been draw	ve been delivered n in this box.						
Box 9	If the PID evolved be provided togeth	after the Original Qua her with the reasons fo	ilification or after the or the changes. Majo	last Extension of Qualific or changes shall be clearl	ation, adequate details of suc marked.	ch evolution shall						
Box 10	Identify the currer arranged as close	nt PID issue status, c as possible to the rec	late and actual date quired date of extens	e of verification. The date ion.	of verification of the currer	nt PID should be						
Box 11	This box can be of practices, procedu out in accordance	completed only after a rres, material, etc. use with the requirements	a physical visit to th d in manufacturing t of ESCC Basic Spe	e plant to confirm that no ne components are as de ecification No. 20200 and	unexplained changes occur cribed in the PID. This surve ts findings shall be recorded	rred and that the y shall be carried l.						
Box 12	Provide details o Nonconformance(satisfactory results	f, or reference to, a s) (NCCS) occurred d s.	ny Destructive Phy luring the qualification	sical Analysis (DPA) ar n validity period, stating i	d Failure Analysis reports established corrective actio	as well as any n have produced						
Box 13	Enter only the na Coordinator.	me of the Executive	Member (i.e., CNES	S, DLR, ESTEC, etc.) an	d the signature of the respo	onsible Executive						
Box 14	To be used when the relevant Box. I	there is a need to exp Box 14 can be broken	band any of the boxe into 14a, 14b, etc. i	es from 1 through 12. Ide several boxes have to be	tify box affected and referer expanded.	nce the Box 14 in						
Box 15	Fill in Table as rec	uested.										
Box 16	Any additional act by the ESCC Exec	ion deemed necessar cutive should be listed	y by the Executive I I herein or the reaso	Member to bring the subn n(s) to accept the noncon	itted data to a standard likel pliance.	y to be accepted						
Box 17	All Executive Mana entry, letters to the	ager recommendation manufacturer, etc. s	s on the application hall be entered clear	tself, special conditions o ly in Box 19, signed by th	restrictions, modifications of e representative for ESA, and	the QPL or QML d dated.						
Box 18	Fill in Table as rec	uested.										
Box 19	Confidential Detail	s of PID changes incl	uding those of a cor	fidential nature, shall be p	rovided.							
Box 20	State noncomplia shall be sequentia	nce with reference to Ily numbered. If releva	specification(s) and ant state 'None'.	paragraph(s). To simplif	reference in Box 16 each	nonconformance						
Box 21	Any additional act by the ESCC Exec	ion deemed necessar cutive should be listed	y by the Executive I herein or the reaso	Member to bring the subn n(s) to accept the noncon	itted data to a standard likel pliance.	y to be accepted						
Box 22	Additional Comme	ents.										